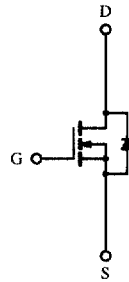
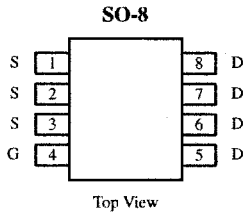


N-Channel 80-V Rated MOSFET

Product Summary

V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A)
80	0.035 @ V _{GS} = 10 V	± 6.0
	0.040 @ V _{GS} = 6.0 V	± 5.5

TrenchFET™
Power MOSFETS



N-Channel MOSFET

Absolute Maximum Ratings (T_A = 25°C Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	80	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150°C) ^a	I _D	T _A = 25°C	± 6.0
		T _A = 70°C	± 4.8
Pulsed Drain Current	I _{DM}	± 40	A
Continuous Source Current (Diode Conduction) ^a	I _S	2.1	W
Maximum Power Dissipation ^a	P _D	T _A = 25°C	
		T _A = 70°C	1.6
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

Thermal Resistance Ratings

Parameter	Symbol	Limit	Unit
Maximum Junction-to-Ambient ^a	R _{thJA}	50	°C/W

Notes

a. Surface Mounted on FR4 Board, t ≤ 10 sec.

Updates to this data sheet may be obtained via facsimile by calling Siliconix FaxBack, 1-408-970-5600. Please request FaxBack document #70645.

3
SOIC-8

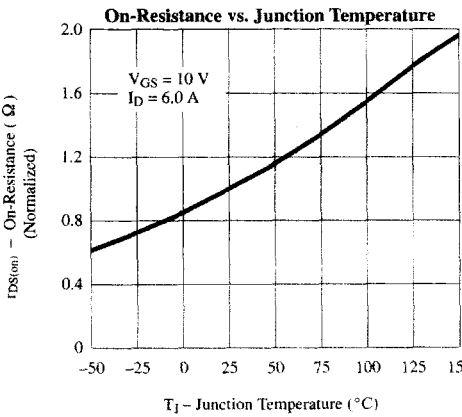
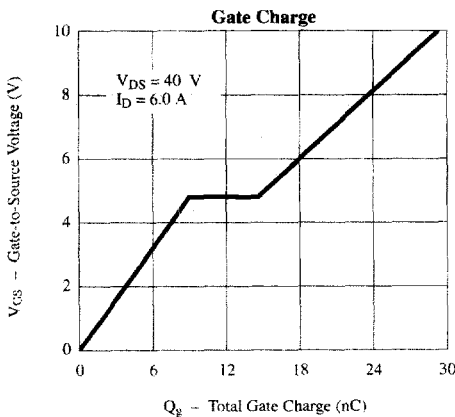
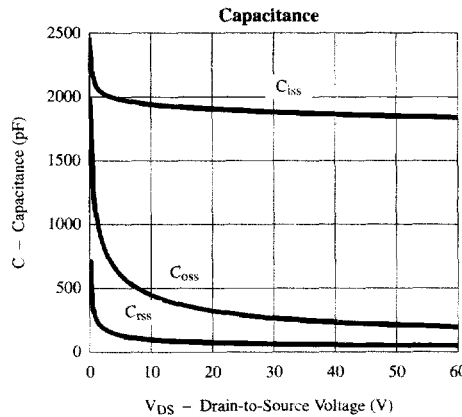
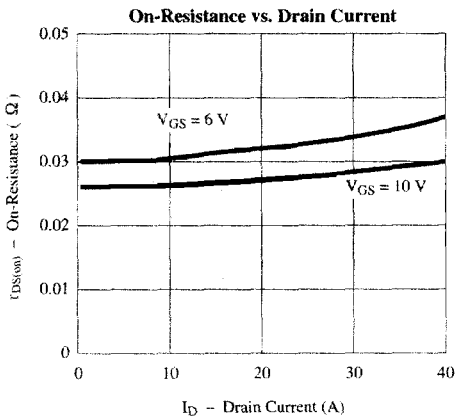
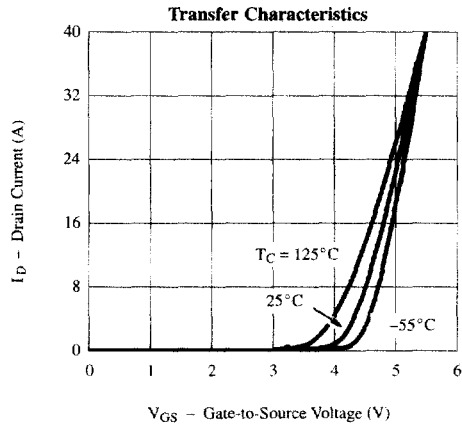
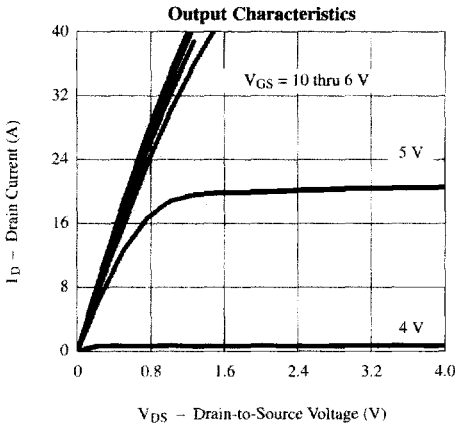
Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ ^a	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2			V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			20	
On-State Drain Current ^b	$I_{D(on)}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			A
Drain-Source On-State Resistance ^b	$r_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 6.0 \text{ A}$		0.026	0.035	Ω
		$V_{GS} = 6.0 \text{ V}, I_D = 5.5 \text{ A}$		0.030	0.040	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 6.0 \text{ A}$		25		S
Diode Forward Voltage ^b	V_{SD}	$I_S = 2.1 \text{ A}, V_{GS} = 0 \text{ V}$			1.2	V
Dynamic^a						
Total Gate Charge	Q_g	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6.0 \text{ A}$		30	50	nC
Gate-Source Charge	Q_{gs}			9		
Gate-Drain Charge	Q_{gd}			5.6		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 40 \text{ V}, R_L = 30 \Omega$ $I_D \cong 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 6 \Omega$		12.5	25	ns
Rise Time	t_r			12.5	25	
Turn-Off Delay Time	$t_{d(off)}$			52	80	
Fall Time	t_f			22	40	
Source-Drain Reverse Recovery Time	t_{rr}	$I_F = 2.1 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$		50	80	

Notes

- a. For design aid only; not subject to production testing.
 b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

Typical Characteristics (25°C Unless Otherwise Noted)



3
SOIC-8

Typical Characteristics (25°C Unless Otherwise Noted)

